

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	12	((("20050210429") or ("5377201") or ("5657240") or ("6286126") or ("20034014201") or ("6560571") or ("6567967")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2006/04/27 13:06
S2	4835	((reliability or consistency) with (verif\$7 or analy\$4)) and (complexity or density)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 08:10
S3	2702	((transistor or FET) near4 (number or value or quantity)) same (complexity or density)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 14:20
S4	23	S2 and S3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 13:26
S5	22	time and S4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 13:27
S6	1	(run near4 time) and S5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 13:27
S7	1	(run\$4 near4 time) and S5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 13:55
S8	131120	run\$4 near4 time	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 08:14
S9	683	S2 and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 13:56
S10	6	((transistor or FET) same (complexity or density)) and S9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 13:57
S11	1919	((transistor or FET) near4 (number or value or quantity)) with (abort\$3 or no or reject)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 08:03

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S12	26	((transistor or FET) near4 (number or value or quantity)) with (abort\$3 or no or reject\$3 or eject\$3 or refus\$3 or declin\$3) with (analy\$4 or verif\$7 or exam\$7 or check\$3 or test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 14:41
S13	0	S8 and S12	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 14:39
S14	149	((transistor or FET) near4 (number or value or quantity)) same ((abort\$3 or no or reject\$3 or eject\$3 or refus\$3 or declin\$3) with (analy\$4 or verif\$7 or exam\$7 or check\$3 or test\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 15:32
S15	6	S8 and S14	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 14:43
S16	40406	((abort\$3 or reject\$3 or eject\$3 or refus\$3 or declin\$3) with (analy\$4 or verif\$7 or exam\$7 or check\$3 or test\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 15:33
S17	468	S2 and S16	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 15:34
S18	89	S8 and S17	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 15:35
S19	23	((large near2 scale) or VLSI) and S18	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/27 15:36
S20	218436	(transistor or FET or path) with (threshold or limit\$3 or max or maximum or maxima)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 08:06
S21	19701	electromigration or (electro adj migration) or electro-migration or self-heating or (self adj heating) or selfheating	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 08:09
S22	1481	S20 and S21	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 08:09

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S23	801	((reliability or consistency) and S22	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 08:09
S24	141	((reliability or consistency) same (verif\$7 or analy\$4 or valid\$5 or exam\$7 or check\$3 or test\$3 or analy\$5)) and S23	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 08:12
S25	97	((reliability or consistency) with (verif\$7 or analy\$4 or valid\$5 or exam\$7 or check\$3 or test\$3 or analy\$5)) and S23	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 08:12
S26	15	("706"/\$.ccls. or "703"/\$.ccls. or "714"/\$.ccls.) and S25	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 08:13
S27	2	(run\$4 near4 time) and S26	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 11:09
S28	5	((run\$4 or execut\$3 or compil\$5) near4 (time or duration)) and S26	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 11:45
S29	40	"5446676"	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 11:44
S30	10	((run\$4 or execut\$3 or compil\$5) near4 (time or duration)) and S29	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 11:53
S31	7	S20 and S30	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2006/04/28 11:53